

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Takuji HIMENO et al.  
International Application No.: PCT/JP03/08432  
International Filing Date: July 2, 2003  
For: IMAGE DATA PROCESSING APPARATUS AND METHOD

745 Fifth Avenue  
New York, NY 10151

**EXPRESS MAIL**

Mailing Label Number: EV206809613US

Date of Deposit: January 6, 2005

I hereby certify that this paper or fee is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" Service under 37 CFR 1.10 on the date indicated above and is addressed to Mail Stop PCT, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Barnet Shindelman  
(Type or printed name of person mailing paper or fee)

[Signature]  
(Signature of person mailing paper or fee)

**INFORMATION DISCLOSURE STATEMENT**

Mail Stop PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/08432. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

Receipt date: 01/06/2005

01520445  
10920445 06 JAN 2005  
DT15M 037PTO 06 JAN 2005  
PATENT  
450100-04677

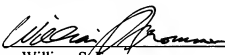
**REMARKS**

Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP  
Attorneys for Applicants

By:   
William S. Frommer  
Reg. No. 25,506  
Tel. (212) 588-0800

Enclosures

DTIS Rec 06 JAN 2005

Sheet 1 of 1

Based on Form PTO-1449 (3/90)	ATTY. DOCKET NO. 450100-04677	SERIAL NO. 10520445 Filed Concurrently Herewith
	LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	
	APPLICANT Takuji HIMENO et al.	
FILING DATE Filed Concurrently Herewith		GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/D.H./	AL	JP 10-308942	11/17/98	Japan			
/D.H./	AM	JP 2000-92448	03/31/00	Japan			
/D.H./	AN	JP 2001-275077	10/05/01	Japan			
	AO						
	AP						

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	
	AR	
	AS	

EXAMINER  /David Harvey/	DATE CONSIDERED  03/29/2009
<p>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	